Unit: mm

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TOSHIBA Transistor Silicon NPN Epitaxial Type

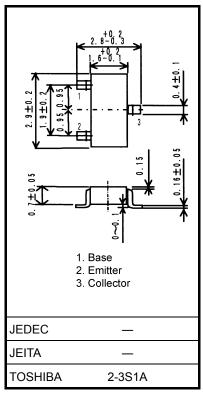
# 2SC5703

High-Speed Switching Applications DC-DC Converter Applications Strobe Applications

- High DC current gain:  $h_{FE} = 400 \text{ to } 1000 \text{ (IC} = 0.5 \text{ A)}$
- Low collector-emitter saturation voltage:  $V_{CE (sat)} = 0.12 \text{ V (max)}$
- High-speed switching: tf = 55 ns (typ.)

### Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V <sub>CBO</sub>	100	V	
Collector-emitter voltage		V <sub>CEX</sub>	80	V	
Collector-emitter voltage		V <sub>CEO</sub>	50	V	
Emitter-base voltage		V <sub>EBO</sub>	7	V	
Collector current	DC	IC	4	Α	
	Pulse	I <sub>CP</sub>	7		
Base current		IB	400	mA	
Collector power dissipation	DC	PC	800	mW	
	t = 10 s	(Note 1)	1250		
Junction temperature		Tj	150	°C	
Storage temperature range		T <sub>stg</sub>	–55 to 150	°C	



Weight: 0.01 g (typ.)

- Note 1: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm<sup>2</sup>)
- Note 2: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

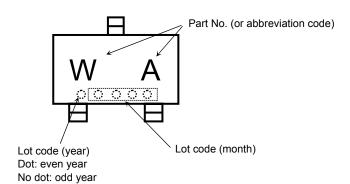
# Efectivica Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I <sub>CBO</sub>	V <sub>CB</sub> = 100 V, I <sub>E</sub> = 0	_	_	100	nA
Emitter cut-off current		I <sub>EBO</sub>	$V_{EB} = 7 \text{ V, } I_{C} = 0$	_	_	100	nA
Collector-emitter breakdown voltage		V (BR) CEO	$I_C = 10 \text{ mA}, I_B = 0$	50	_	_	٧
DC current gain		h <sub>FE</sub> (1)	$V_{CE} = 2 \text{ V}, I_{C} = 0.5 \text{ A}$	400	_	1000	
		h <sub>FE</sub> (2)	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 1.6 A	200	_	_	
Collector-emitter saturation voltage		V <sub>CE</sub> (sat)	I <sub>C</sub> = 1.6 A, I <sub>B</sub> = 32 mA	_	_	0.12	V
Base-emitter saturation voltage		V <sub>BE</sub> (sat)	I <sub>C</sub> = 1.6 A, I <sub>B</sub> = 32 mA	_	_	1.10	V
Collector output capacitance		C <sub>ob</sub>	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0, f = 1 MHz	_	26	_	pF
Switching time	Rise time	t <sub>r</sub>	See Figure 1 circuit diagram.	_	45	_	ns
	Storage time	t <sub>stg</sub>	$V_{CC} \simeq 30 \text{ V}, R_L = 19 \Omega$	_	700	_	
	Fall time	t <sub>f</sub>	$I_{B1} = -I_{B2} = 53.3 \text{ mA}$	_	55	_	

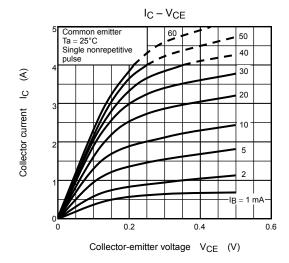
# $\begin{array}{c|c} & V_{CC} \\ & \downarrow^{20~\mu s} \\ & \downarrow^{1}_{B1} \\ & \downarrow^{1}_{B2} \\ &$

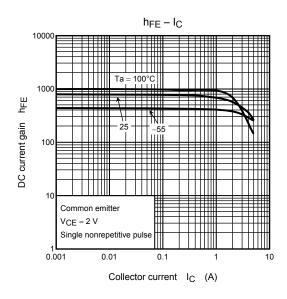
Figure 1 Switching Time Test Circuit & Timing Chart

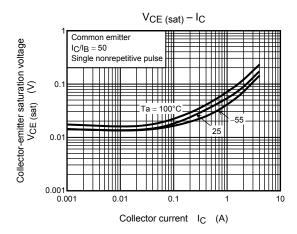
## Marking

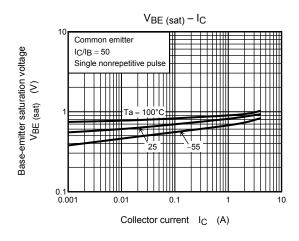


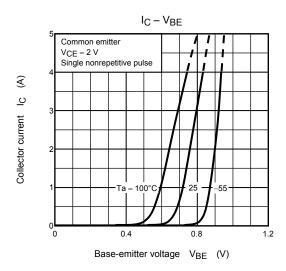
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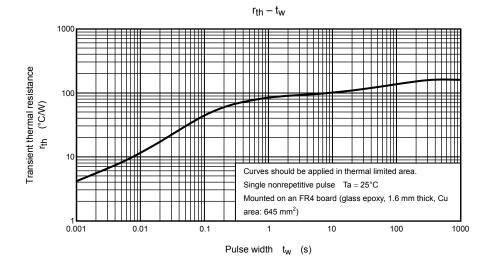




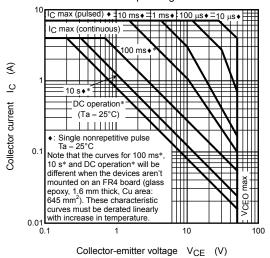


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### Safe Operating Area



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